

Seminář odd. 26

Tenkých vrstev a nanostruktur

Fyzikální ústav AVČR, Cukrovarnická 10, Praha 6

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TÉMA

Raman spectroscopy of graphene – basic characterization and beyond

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Raman spectroscopy is the undisputed method of choice for a simple, fast and non-destructive characterization of graphene. Its capabilities go far beyond the commonly used assessment of quality a layer number. The lecture will review some of the recent advances as well as pitfalls in determining various states and properties of graphene systems, like disentangling strain level and charge carrier concentration, determining bending rigidity or investigating interaction between individual layers in bilayer graphene.

odborný garant: *Ing. Pavel Jelínek, PhD.*